

List of Publications of (2010-2011)

Journals

Dr. A. K. Atta

1. **Atta, A. K.**; Pathak, T. A general and diastereoselective route to five membered heterocycles and carbocycles from acyclic vinyl sulfone-modified carbohydrates. *Eur. J. Org. Chem.* **2010**, 872-881.
2. **Atta, A. K.**; Pathak, T. A Tandem Michael-SN2 Mediated General Route to Six-membered Heterocycles and Carbocycles. *Eur. J. Org. Chem.* **2010**, 6810-6819.

Dr. K. R. Singh

1. P. K. Das and K. Ratan Singh, "**2-graphoidal covering number of a graph**", International Journal of Pure and Applied Mathematics, 72(2) (2011), 125-135
2. K. R. Singh and P .K. Das, "**self-graphoidal graphs**", Thai Journal of Mathematics, 8(3) (2010), 575-579.

International Conferences

Santanu Maity

1. Sonali Das, Avra Kundu, Santanu Maity, Sayantan Dhar, Bhaskar Gupta, "**Novel Compact CPW Filter for MICs Using Metamaterial Structures**", *IEEE Conference, 2011*
2. Amrita Chakraborty, Avra Kundu, Sayantan Dhar, Santanu Maity, Sayan Chatterjee, Bhaskar Gupta, "**Compact K-Band Distributed RF MEMS Phase Shifter Based on High-Speed Switched Capacitors**", *IEEE conference, 2011*
3. Avra Kundu, S. maity, S. ghosh Hiranmay Saha Avra Kundu, Santanu Maity, Sugato Ghosh under Prof. H. Saha won the best poster award for poster titled "Fabrication & Packaging of MEMS based microheater with co-planar IDE for gas sensing applications" in National Conference on Sensors & Actuators: Science to Technology (NCSA) 2011

Abir Jyoti Mondal

1. Rajib Kar, Vikas Maheshwari, **Abir Mandal**, Ashis Kr Mal, Anup Bhattacharjee, "Closed Form Modelling for Delay and Slew Metrics for On-Chip VLSI RC Interconnect for Ramp Inputs Using F- Distribution", *2010 IEEE Symposium on Industrial Electronics and Applications (ISIEA 2010)*, October 3-5, 2010, Penang, Malaysia.
2. Rajib Kar; **Abirjyoti Mondal**; Vikas Maheshwari; Ashis Kr Mal; and Anup Kumar Bhattacharjee "A Closed Form Expression for Slew Metric for On-chip VLSI RC Interconnects using F-distribution Function", *14th VLSI Design & Test Symposium, VDAT, 2010*.